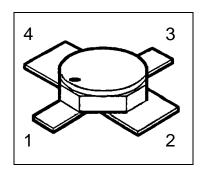


# HiRel NPN Silicon Germanium RF Transistor

- HiRel Discrete and Microwave Semiconductor
- High gain ultra low noise RF transistor
- Outstanding noise figure F = 0.7 dB at 1.8 GHz
   Outstanding noise figure F = 1.0 dB at 6 GHz
- Hermetically sealed microwave package



**ESD**: Electrostatic discharge sensitive device, observe handling precautions!

Туре	Marking	Pin Configuration				Package
		1	2	3	4	
BFY740B	-	С	Е	В	Е	Micro-X

### **Maximum Ratings**

Parameter	Symbol	Values	Unit	
Collector-emitter voltage $T_a > 0  ^{\circ}C$ $T_a \leq 0  ^{\circ}C$	V <sub>CEO</sub>	4.0 3.5	V	
Collector-base voltage	$V_{CBO}$	13	V	
Emitter-base voltage	$V_{EBO}$	1.2	V	
Collector current 1)	I <sub>C</sub>	30	mA	
Base current	I <sub>B</sub>	3	mA	
Junction temperature	T <sub>j</sub>	175	°C	
Operating temperature range	T <sub>op</sub>	-65+175	°C	
Storage temperature range	T <sub>stg</sub>	-65+175	°C	
Thermal Resistance	•	•		
Junction-soldering point 2)	R <sub>th JS</sub>	400	K/W	

### Notes.:

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<sup>1)</sup> For  $T_S \le 125^{\circ}\text{C}$ . For  $T_S > 125^{\circ}\text{C}$  derating is required.

<sup>2)</sup>  $T_S$  is measured on the emitter lead at the soldering point to the pcb.



## **Electrical Characteristics**

at T<sub>A</sub>=25°C; unless otherwise specified

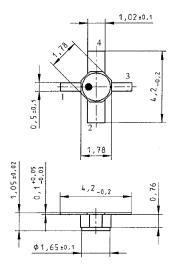
Parameter	Symbol	Values			Unit
		min.	typ.	max.	
DC Characteristics	·	·	•		
Collector-base cutoff current	I <sub>CBO</sub>	-	-	10	μΑ
$V_{CB} = 5 \text{ V}, I_E = 0$					
Collector-emitter cutoff current 1)	I <sub>CEX</sub>	-	-	200	μΑ
$V_{CE}=4.0~V,~I_B=0.1~\mu A$					
Emitter-base cuttoff current	I <sub>EBO</sub>	-	-	5	μΑ
$V_{EB} = 1.2 \text{ V}, I_{C} = 0$					
DC current gain	h <sub>FE</sub>	130	270	480	-
$I_C = 20$ mA, $V_{CE} = 3$ V					
AC Characteristics					
Collector-base capacitance	ССВ	-	0.07	-	pF
$V_{CB} = 2 \text{ V}, V_{BE} = \text{vbe} = 0, f = 1 \text{ MHz}$					
Collector-emitter capacitance	C <sub>CE</sub>	-	0.45	-	pF
$V_{CE} = 2 \text{ V}, V_{BE} = \text{vbe} = 0, f = 1 \text{ MHz}$					
Emitter-base capacitance	C <sub>EB</sub>	-	0.6	-	pF
$V_{EB} = 0.5V, V_{CB} = vcb = 0, f = 1 MHz$					
Noise Figure ( $Z_S = Z_{sopt}$ )	F				dB
$I_C = 8 \text{ mA}, V_{CE} = 3 \text{ V}, f = 1.8 \text{ GHz}$		-	0.7	-	
$I_C = 8 \text{ mA}, V_{CE} = 3 \text{ V}, f = 6.0 \text{ GHz}$	1.2	-	1.0	-	
Insertion power gain ( $Z_S = Z_L = 50 \Omega$ )	$\left S_{21e}\right ^2$				dB
$I_C$ = 20 mA, $V_{CE}$ = 3 V, f = 1.8 GHz $I_C$ = 20 mA, $V_{CE}$ = 3 V, f = 6.0 GHz		-	24 14	-	
Power gain $(Z_S = Z_{Sopt}, Z_L = Z_{Lopt})$	G <sub>ms</sub> <sup>2)</sup>				dB
$I_C = 20 \text{ mA}, V_{CE} = 3 \text{ V}, f = 1.8 \text{ GHz}$		-	26.5	-	
Power gain $(Z_S = Z_{Sopt}, Z_L = Z_{Lopt})$	G <sub>ma</sub> <sup>2)</sup>				dB
$I_C = 20 \text{ mA}, V_{CE} = 3 \text{ V}, f = 6.0 \text{ GHz}$		-	18.3	-	

Notes.:
1) This Test assures V(BR)CE0 > 4.0V

2) 
$$G_{ma} = \left| \frac{S21}{S12} \right| (k - \sqrt{k^2 - 1}), \quad G_{ms} = \left| \frac{S21}{S12} \right|$$



# Micro-X Package



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